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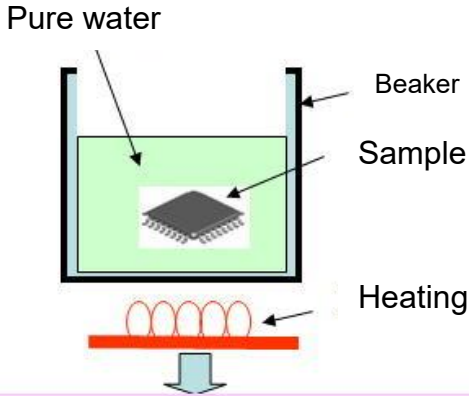
# 1986

## Introduction of ion chromatography testing

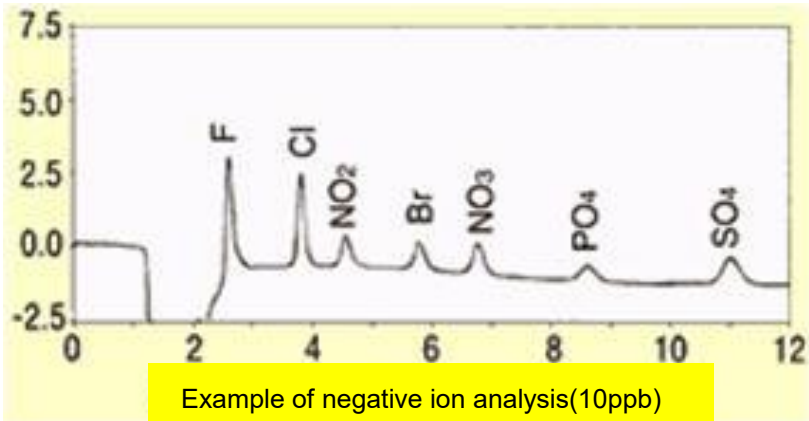
### ~ Packaging ~

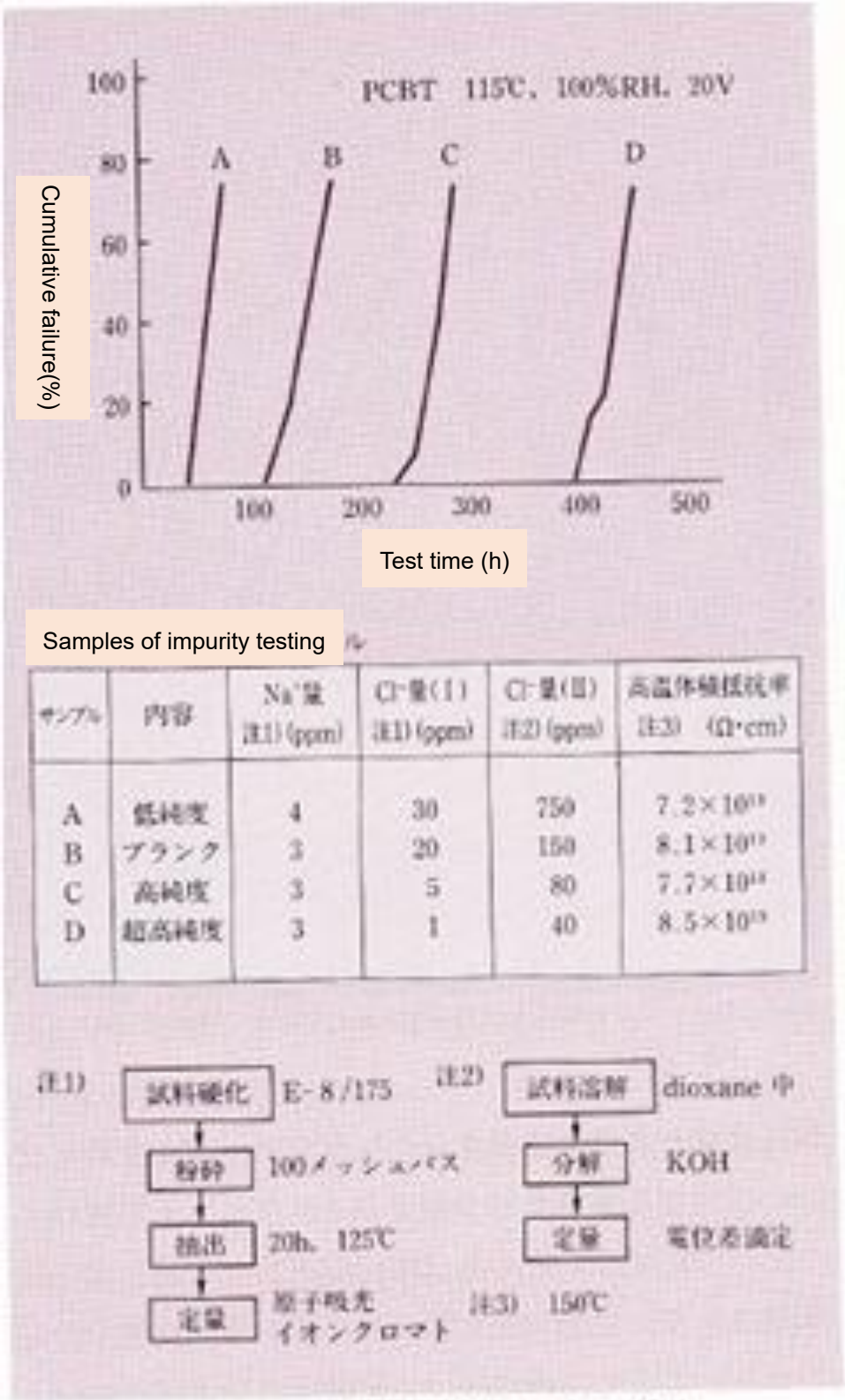
Around 1986, Musashi Works of Hitachi found that impurity ions attached to semiconductor packages were involved in corrosion of aluminum interconnects of plastic mold LSI devices under moisture resistance test conditions, and they introduced the management of attached impurities to the assembled devices and to the packaging materials. They introduced a method of controlling halide ions at the level of ppb or less.

Introduction of impurity management by ion chromatographic method dramatically improved the temperature and humidity resistance reliability level, and plastic molded devices started to be used as the main packages in place of hermetically sealed packages.



Analysis of impurity ions desolving out into pure water  
 (Sensitivity is improved on condensation)  
 Pure water





Relation between impurity content in mold resin material and moisture test reliability